



MRL

FREDERICK SEITZ MATERIALS RESEARCH LABORATORY



11:00 AM, Tuesday, October 14, 2008
Room 280 MRL

Total reflection x-ray fluorescence (TXRF): new developments and applications

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TXRF - total reflection x-ray fluorescence - is a well established technique, which is being traditionally used in semiconductor industry for analysis of thin layers.

Recently there are new developments in this area, using low power x-ray tubes and EDX detectors. XRF basics will be discussed with explanation of the wavelength dispersive (WD) XRF and (energy dispersive) ED XRF.

Principles of TXRF, major features of the new instrument - Picofox and its advantages will be shown. Several applications of this instrument in the pharmaceutical, food and vitamin supplements industry will be discussed as well.

Facilities Seminar Series